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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	84
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 25x14b; D/A 3x8b, 3x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TFLGA
Supplier Device Package	100-TFLGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a6782a01clj-ac0

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## Table 1.3 System (2 of 2)

Feature	Functional description
Memory Protection Unit (MPU)	Four Memory Protection Units (MPUs) and a CPU stack pointer monitor function are provided for memory protection. See section 15, Memory Protection Unit (MPU) in User's Manual.
Watchdog Timer (WDT)	The Watchdog Timer (WDT) is a 14-bit down-counter. It can be used to reset the MCU when the counter underflows because the system has run out of control and is unable to refresh the WDT. In addition, a non-maskable interrupt or interrupt can be generated by an underflow. A refresh-permitted period can be set to refresh the counter and used as the condition to detect when the system runs out of control. See section 25, Watchdog Timer (WDT) in User's Manual.
Independent Watchdog Timer (IWDT)	The Independent Watchdog Timer (IWDT) consists of a 14-bit down-counter that must be serviced periodically to prevent counter underflow. It can be used to reset the MCU or to generate a non-maskable interrupt/interrupt for a timer underflow. Because the timer operates with an independent, dedicated clock source, it is particularly useful in returning the MCU to a known state as a fail-safe mechanism when the system runs out of control. The IWDT can be triggered automatically on a reset, underflow, refresh error, or by a refresh of the count value in the registers. See section 26, Independent Watchdog Timer (IWDT) in User's Manual.

#### Table 1.4 Event link

Feature	Functional description
Event Link Controller (ELC)	The Event Link Controller (ELC) uses the interrupt requests generated by various peripheral modules as event signals to connect them to different modules, enabling direct interaction between the modules without CPU intervention. See section 18, Event Link Controller (ELC) in User's Manual.

## Table 1.5Direct memory access

Feature	Functional description
Data Transfer Controller (DTC)	A Data Transfer Controller (DTC) module is provided for transferring data when activated by an interrupt request. See section 17, Data Transfer Controller (DTC) in User's Manual.
DMA Controller (DMAC)	A 4-channel DMA Controller (DMAC) module is provided for transferring data without the CPU. When a DMA transfer request is generated, the DMAC transfers data stored at the transfer source address to the transfer destination address. See section 16, DMA Controller (DMAC) in User's Manual.





Figure 1.5 Pin assignment for 64-pin LQFP (top view)





Figure 1.9 Pin assignment for 40-pin QFN (top view)



# 2. Electrical Characteristics

Unless otherwise specified, the electrical characteristics of the MCU are defined under the following conditions:

 $VCC^{*1} = AVCC0 = VCC\_USB^{*2} = VCC\_USB\_LDO^{*2} = 1.6 \text{ to } 5.5V, VREFH = VREFH0 = 1.6 \text{ to } AVCC0, VBATT = 1.6 \text{ to } 3.6V, VSS = AVSS0 = VREFL = VREFL0 = VSS\_USB = 0V, T_a = T_{opr}$ 

Note 1. The typical condition is set to VCC = 3.3V.

Note 2. When USBFS is not used.

Figure 2.1 shows the timing conditions.



#### Figure 2.1 Input or output timing measurement conditions

The recommended measurement conditions for the timing specification of each peripheral provided are for the best peripheral operation. Make sure to adjust the driving abilities of each pin to meet your conditions.

Each function pin used for the same function must select the same drive ability. If the I/O drive ability of each function pin is mixed, the AC specification of each function is not guaranteed.



# Table 2.6 I/O I<sub>OH</sub>, I<sub>OL</sub> (2 of 2) Conditions: VCC = AVCC0 = VCC\_USB = VCC\_USB\_LCO = 1.6 to 5.5 V

Parameter	Symbol	Min	Тур	Мах	Unit		
Permissible output current	Ports P212, P213 -		I <sub>ОН</sub>	-	-	-4.0	mA
(max value per pin)			I <sub>OL</sub>	-	-	4.0	mA
	Port P408	Low drive*1	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	4.0	mA
		Middle drive for IIC	I <sub>ОН</sub>	-	-	-8.0	mA
		VCC = 2.7 to 5.5 V	I <sub>OL</sub>	-	-	8.0	mA
		Middle drive*2	I <sub>ОН</sub>	-	-	-20.0	mA
		VCC = 3.0 to 5.5 V	I <sub>OL</sub>	-	-	20.0	mA
	Port P409	Low drive*1	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	4.0	mA
		Middle drive <sup>*2</sup>	I <sub>ОН</sub>	-	-	-8.0	mA
		VCC = 2.7 to 3.0 V	I <sub>OL</sub>	-	-	8.0	mA
		Middle drive <sup>*2</sup> VCC = 3.0 to 5.5 V	I <sub>ОН</sub>	-	-	-20.0	mA
			I <sub>OL</sub>	-	-	20.0	mA
	Ports P100 to P115, P201 to P204, P300 to P307, P500 to P503, P600 to P603,	Low drive*1	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	4.0	mA
	(total 41 pins)	Middle drive*2	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	8.0	mA
	Ports P914, P915	-	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	4.0	mA
	Other output pin*3	Low drive*1	I <sub>ОН</sub>	-	-	-4.0	mA
			I <sub>OL</sub>	-	-	4.0	mA
		Middle drive*2	I <sub>ОН</sub>	-	-	-8.0	mA
			I <sub>OL</sub>	-	-	8.0	mA
Permissible output current	Total of ports P000 to P008, P010	to P015	ΣI <sub>OH (max)</sub>	-	-	-30	mA
			ΣI <sub>OL (max)</sub>	-	-	30	mA
	Ports P914, P915		Σl <sub>OH (max)</sub>	-	-	-2.0	mA
			ΣI <sub>OL (min)</sub>	-	-	2.0	mA
	Total of all output pin <sup>*5</sup>		ΣI <sub>OH (max)</sub>	-	-	-60	mA
			ΣI <sub>OL (max)</sub>	-	-	60	mA

Caution: To protect the reliability of the MCU, the output current values should not exceed the values in this table. The average output current indicates the average value of current measured during 100 µs.

Note 1. This is the value when low driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 2. This is the value when middle driving ability is selected with the Port Drive Capability bit in PmnPFS register.

Note 3. Except for ports P200, P214, P215, which are input ports.

Note 4. This is the value when middle driving ability for IIC Fast-mode is selected with the Port Drive Capability bit in PmnPFS register.

Note 5. For details on the permissible output current used with CTSU, see section 2.11, CTSU Characteristics.





Figure 2.17 Voltage dependency in high-speed operating mode (reference data)





Figure 2.18 Voltage dependency in middle-speed operating mode (reference data)







Figure 2.23 Temperature dependency of RTC operation with VCC off (reference data)



# 2.2.10 VCC Rise and Fall Gradient and Ripple Frequency

#### Table 2.15 Rise and fall gradient characteristics

Conditions: VCC = AVCC0 = 0 to 5.5 V

Parameter		Symbol	Min	Тур	Max	Unit	Test conditions
Power-on VCCVoltage monitor 0 reset disabled at startup (normal startup)		SrVCC	0.02	-	2	ms/V	-
	Voltage monitor 0 reset enabled at startup*1		0.02	-	-		
	SCI/USB boot mode*2		0.02	-	2		

Note 1. When OFS1.LVDAS = 0.

Note 2. At boot mode, the reset from voltage monitor 0 is disabled regardless of the value of OFS1.LVDAS bit.

#### Table 2.16 Rising and falling gradient and ripple frequency characteristics

Conditions: VCC = AVCC0 = VCC\_USB = 1.6 to 5.5 V

The ripple voltage must meet the allowable ripple frequency  $f_{r(VCC)}$  within the range between the VCC upper limit (5.5 V) and lower limit (1.6 V).

When VCC change exceeds VCC ±10%, the allowable voltage change rising/falling gradient dt/dVCC must be met.

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Allowable ripple frequency	f <sub>r (VCC)</sub>	-	-	10	kHz	Figure 2.24 $V_{r (VCC)} \leq VCC \times 0.2$
		-	-	1	MHz	Figure 2.24 $V_{r (VCC)} \leq VCC \times 0.08$
		-	-	10	MHz	Figure 2.24 $V_{r (VCC)} \leq VCC \times 0.06$
Allowable voltage change rising and falling gradient	dt/dVCC	1.0	-	-	ms/V	When VCC change exceeds VCC ±10%



Figure 2.24 Ripple waveform



## 2.3.4 Wakeup Time

Table 2.24	Timing of recovery from low power modes (1)
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Parameter				Symbol	Min	Тур	Max	Unit	Test conditions
Recovery time from Software Standby mode*1	High-speed mode	Crystal resonator connected to	System clock source is main clock oscillator (20 MHz)*2	t <sub>SBYMC</sub>	-	2	3	ms	Figure 2.34
	main clock oscillator	System clock source is PLL (48 MHz) with main clock oscillator <sup>*2</sup>	t <sub>SBYPC</sub>	-	2	3	ms		
		External clock input to main clock oscillator	System clock source is main clock oscillator (20 MHz) <sup>*3</sup>	t <sub>SBYEX</sub>	-	14	25	μs	
			System clock source is PLL (48 MHz) with main clock oscillator* <sup>3</sup>	t <sub>SBYPE</sub>	-	53	76	μs	-
		System clock source is HOCO <sup>*4</sup> (HOCO clock is 32 MHz)		t <sub>SBYHO</sub>	-	43	52	μs	
		System clock source is HOCO <sup>*4</sup> (HOCO clock is 48 MHz)		t <sub>SBYHO</sub>	-	44	52	μs	
		System clock source is HOCO <sup>*5</sup> (HOCO clock is 64 MHz)		t <sub>SBYHO</sub>	-	82	110	μs	
		System clock sou	urce is MOCO	t <sub>SBYMO</sub>	-	16	25	μs	

Note 1. The division ratio of ICK, FCK, and PCKx is the minimum division ratio within the allowable frequency range. The recovery time is determined by the system clock source.

Note 2. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h.

Note 3. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h.

Note 4. The HOCO Clock Wait Control Register (HOCOWTCR) is set to 05h.

Note 5. The HOCO Clock Wait Control Register (HOCOWTCR) is set to 06h.

#### Table 2.25Timing of recovery from low power modes (2)

Parameter				Symbol	Min	Тур	Max	Unit	Test conditions
Recovery time from Software Standby mode* <sup>1</sup>	Recovery time from Software Standby mode*1 Middle-speed Crystal mode resonator connected to main clock oscillator	Crystal resonator connected to	System clock source is main clock oscillator (12 MHz)* <sup>2</sup>	t <sub>SBYMC</sub>	-	2	3	ms	Figure 2.34
		System clock source is PLL (24 MHz) with main clock oscillator* <sup>2</sup>	t <sub>SBYPC</sub>	-	2	3	ms		
External clock input to main clock oscillator	System clock source is main clock oscillator (12 MHz)* <sup>3</sup>	t <sub>SBYEX</sub>	-	2.9	10	μs			
			System clock source is PLL (24 MHz) with main clock oscillator* <sup>3</sup>	t <sub>SBYPE</sub>	-	49	76	μs	
System clock source is H System clock source is M		System clock sou	urce is HOCO (24 MHz)	t <sub>SBYHO</sub>	-	38	50	μs	
		urce is MOCO	t <sub>SBYMO</sub>	-	3.5	5.5	μs		

Note 1. The division ratio of ICK, FCK, and PCKx is the minimum division ratio within the allowable frequency range. The recovery time is determined by the system clock source.

Note 2. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h.

Note 3. The Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h.



# 2.3.6 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 Trigger Timing

Parameter		Symbol	Min	Мах	Unit	Test conditions	
I/O ports	Input data pulse width		t <sub>PRW</sub>	1.5	-	t <sub>Pcyc</sub>	Figure 2.38
	Input/output data cycle (P002, P003, P004, P007)		t <sub>POcyc</sub>	10	-	us	
POEG	POEG input trigger pulse width		t <sub>POEW</sub>	3	-	t <sub>Pcyc</sub>	Figure 2.39
GPT	Input capture pulse width	Single edge	t <sub>GTICW</sub>	1.5	-	t <sub>PDcyc</sub>	Figure 2.40
		Dual edge		2.5	-		
AGT	AGTIO, AGTEE input cycle	2.7 V ≤ VCC ≤ 5.5 V	t <sub>ACYC</sub> *1	250	-	ns	Figure 2.41
		2.4 V ≤ VCC < 2.7 V		500	-	ns	
		1.8 V ≤ VCC < 2.4 V		1000	-	ns	
		1.6 V ≤ VCC < 1.8 V		2000	-	ns	
	AGTIO, AGTEE input high level width, low-level width	2.7 V ≤ VCC ≤ 5.5 V	t <sub>ACKWH</sub> , t <sub>ACKWL</sub>	100	-	ns	
		2.4 V ≤ VCC < 2.7 V		200	-	ns	
		1.8 V ≤ VCC < 2.4 V		400	-	ns	
		1.6 V ≤ VCC < 1.8 V		800	-	ns	
	AGTIO, AGTO, AGTOA, AGTOB	2.7 V ≤ VCC ≤ 5.5 V	t <sub>ACYC2</sub>	62.5	-	ns	Figure 2.41
	output cycle	2.4 V ≤ VCC < 2.7 V		125	-	ns	
		1.8 V ≤ VCC < 2.4 V	-	250	-	ns	-
		1.6 V ≤ VCC < 1.8 V		500	-	ns	
ADC14	14-bit A/D converter trigger input pulse width		t <sub>TRGW</sub>	1.5	-	t <sub>Pcyc</sub>	Figure 2.42
KINT	KRn (n = 00 to 07) pulse width		t <sub>KR</sub>	250	-	ns	Figure 2.43

### Table 2.31 I/O Ports, POEG, GPT, AGT, KINT, and ADC14 trigger timing

Note 1. Constraints on AGTIO input:  $t_{PCVC} \times 2 < t_{ACYC}$ 

Note: t<sub>Pcyc</sub>: PCLKB cycle, t<sub>PDcyc</sub>: PCLKD cycle



### Figure 2.38 I/O ports input timing



Figure 2.39 POEG input trigger timing







#### Figure 2.41 AGT I/O timing







### Figure 2.43 Key interrupt input timing

# 2.3.7 CAC Timing

## Table 2.32 CAC timing

Parame	ter		Symbol	Min	Тур	Max	Unit	Test conditions
CAC	CACREF input pulse width	$t_{PBcyc}^{*1} \le t_{cac}^{*2}$	t <sub>CACREF</sub>	$4.5 \times t_{cac} + 3 \times t_{PBcyc}^{*1}$	-	-	ns	-
		t <sub>PBcyc</sub> *1 > t <sub>cac</sub> *2		$5 \times t_{cac} + 6.5 \times t_{PBcyc}^{*1}$	-	-	ns	







Table 2.34	SCI timing (2) (1 of 2)

Parame	ameter			Symbol	Min	Max	Unit	Test conditions
Simple	e SCK clock cycle output (master) SCK clock cycle input (slave)		t <sub>SPcyc</sub>	4	65,536	t <sub>Pcyc</sub>	Figure 2.46	
SPI				6	65,536			
	SCK clock high pulse width			t <sub>SPCKWH</sub>	0.4	0.6	t <sub>SPcyc</sub>	
	SCK clock low pulse	width		t <sub>SPCKWL</sub>	0.4	0.6	t <sub>SPcyc</sub>	
	SCK clock rise and fa	and fall time 1.8 V or abo		t <sub>SPCKr,</sub>	-	20	ns	
			1.6 V or above	t <sub>SPCKf</sub>	-	30		
	Data input setup	Master	2.7 V or above	t <sub>SU</sub>	45	-	ns	Figure 2.47 to Figure 2.50
	time		2.4 V or above		55	-		
			1.8 V or above		80	-		
			1.6 V or above		110	-		
		Slave	2.7 V or above		40	-		
			1.6 V or above		45	-		
	Data input hold time	Master		t <sub>H</sub>	33.3	-	ns	
		Slave			40	-		
	SS input setup time		t <sub>LEAD</sub>	1	-	t <sub>SPcyc</sub>		
	SS input hold time	t hold time		t <sub>LAG</sub>	1	-	t <sub>SPcyc</sub>	
	Data output delay	Master	1.8 V or above	t <sub>OD</sub>	-	40	ns	
			1.6 V or above		-	50		
		Slave	2.4 V or above		-	65		
			1.8 V or above		-	100		
			1.6 V or above		-	125		
	Data output hold time	Master	2.7 V or above	t <sub>он</sub>	-10	-	ns	
			2.4 V or above	-	-20	-		
			1.8 V or above		-30	-		
			1.6 V or above		-40	-		
	Slave			-10	-			
	Data rise and fall time	ise and fall Master	1.8 V or above	<sup>t</sup> Dr, <sup>t</sup> Df	-	20	ns	
			1.6 V or above		-	30		
		Slave	1.8 V or above		-	20		
			1.6 V or above		-	30		





Figure 2.56 SPI timing for master when CPHA = 1 and the bit rate is set to PCLKA/2



Figure 2.57 SPI timing for slave when CPHA = 0





#### Figure 2.66 Test circuit for Full-Speed (FS) connection



#### Figure 2.67 Test circuit for Low-Speed (LS) connection

# 2.4.2 USB External Supply

## Table 2.41 USB regulator

Parameter	Min	Тур	Max	Unit	Test conditions	
VCC_USB supply current	VCC_USB_LDO ≥ 3.8V	-	-	50	mA	-
	VCC_USB_LDO ≥ 4.5V	-	-	100	mA	-
VCC_USB supply voltage		3.0	-	3.6	V	-



- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL4 and GND
- $C1 = C2 = C3 = C4 = 0.47 \ \mu F \pm 30\%.$
- Note 2. This is the time required to wait from when the reference voltage is specified using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET[1:0] bits in the LCDM0 register to 01b) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- Note 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

#### [1/4 Bias Method]

#### Table 2.65 Internal voltage boosting method LCD characteristics

Conditions: VCC = 1.8 V to 5.5 V

Parameter	Symbol	Conditions		Min	Тур	Max	Unit	Test conditions
LCD output voltage	V <sub>L1</sub>	C1 to C5*1 = 0.47 µF	VLCD = 04h	0.90	1.0	1.08	V	-
variation range			VLCD = 05h	0.95	1.05	1.13	V	-
			VLCD = 06h	1.00	1.10	1.18	V	-
			VLCD = 07h	1.05	1.15	1.23	V	-
			VLCD = 08h	1.10	1.20	1.28	V	-
			VLCD = 09h	1.15	1.25	1.33	V	-
			VLCD = 0Ah	1.20	1.30	1.38	V	-
			VLCD = 0Bh	1.25	1.35	1.43	V	-
			VLCD = 0Ch	1.30	1.40	1.48	V	-
Doubler output voltage	V <sub>L2</sub>	C1 to C5*1 = 0.47 µF		2V <sub>L1</sub> - 0.08	2V <sub>L1</sub>	2V <sub>L1</sub>	V	-
Tripler output voltage	V <sub>L3</sub>	C1 to C5*1 = 0.47 µF		3V <sub>L1</sub> - 0.12	3V <sub>L1</sub>	3V <sub>L1</sub>	V	-
Quadruply output voltage	V <sub>L4</sub> *4	C1 to C5 <sup>*1</sup> = 0.47 µF		4V <sub>L1</sub> - 0.16	4V <sub>L1</sub>	4V <sub>L1</sub>	V	-
Reference voltage setup time* <sup>2</sup>	t <sub>VL1S</sub>			5	-	-	ms	Figure 2.81
LCD output voltage variation range* <sup>3</sup>	t <sub>VLWT</sub>	C1 to C5*1 = 0.47 µF		500	-	-	ms	

Note 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between V<sub>L1</sub> and GND

C3: A capacitor connected between  $V_{L2}$  and GND

C4: A capacitor connected between  $V_{L3}$  and GND

C5: A capacitor connected between  $V_{L4}$  and GND

 $C1 = C2 = C3 = C4 = C5 = 0.47 \ \mu\text{F} \pm 30\%$ 

Note 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits in the LCDM0 register to 01b) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).

Note 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

Note 4. V<sub>L4</sub> must be 5.5 V or lower.













Revision History	
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#### S3A6 Microcontroller Group Datasheet

Rev.	Date	Summary
1.00	Apr 4, 2017	1st release
1.10	Jun 25, 2018	2nd release

#### Website and Support

Visit the following vanity URLs to learn about key elements of the Synergy Platform, download components and related documentation, and get support.

renesassynergy.com/software
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renesassynergy.com/mcuglossary
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